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In-situ nano-mechanical tests in the light of μ Laue diffraction

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Albufeira, Portugal
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In situ three-points bending tests
of Au nanowires
in the light of μ Laue diffraction

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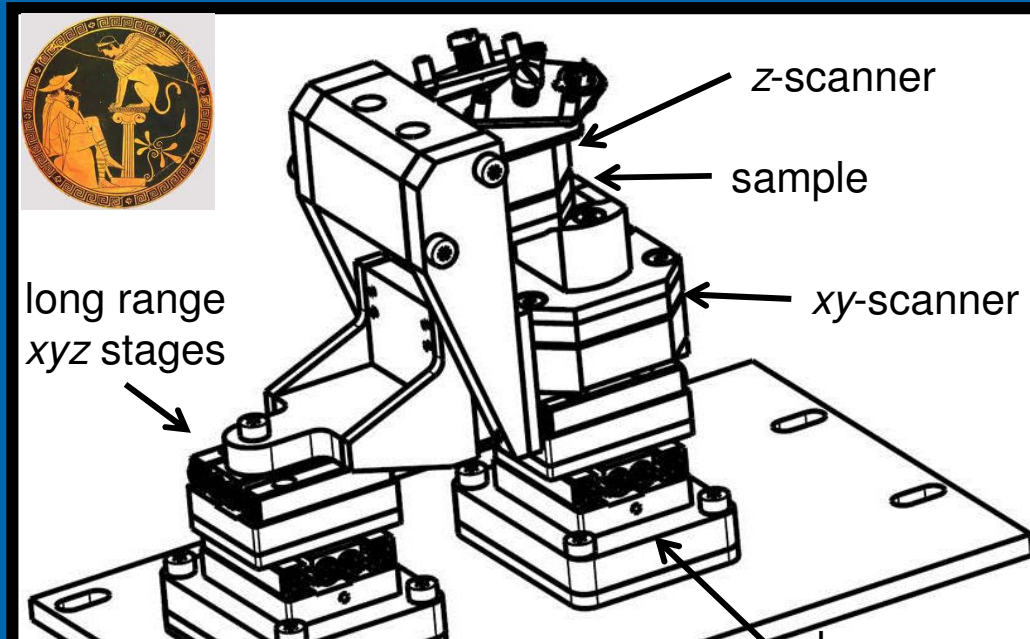
G. Richter

MPI for Intelligent Systems, Stuttgart, Germany



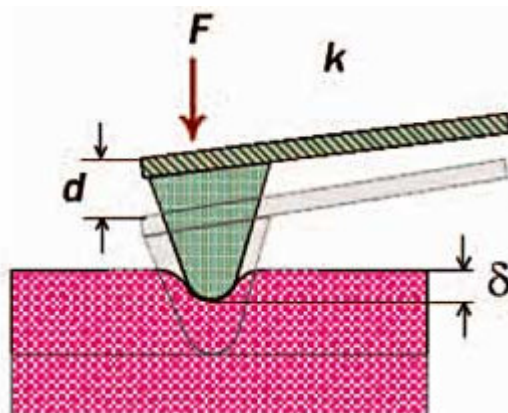
SFINX

Scanning Force microscope for *In situ* Nanofocused X-ray diffraction

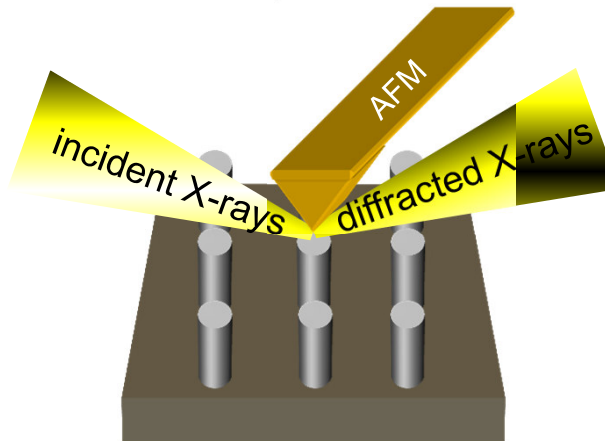


Z. Ren et al.,
J. Synchrotron Radiat.
21 (2014) 1128

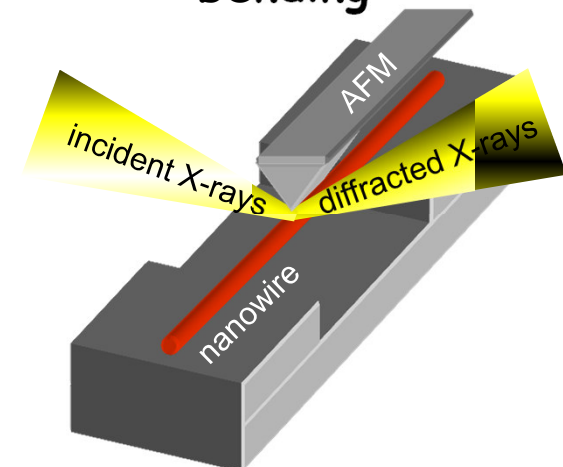
indentation



compression

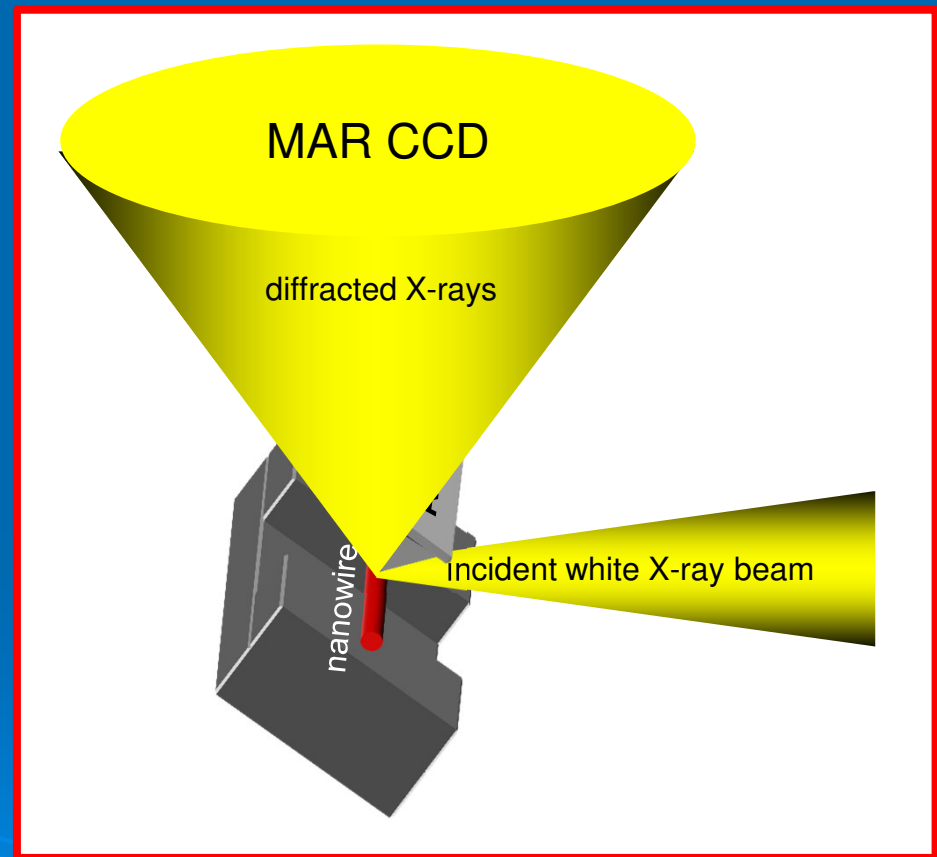
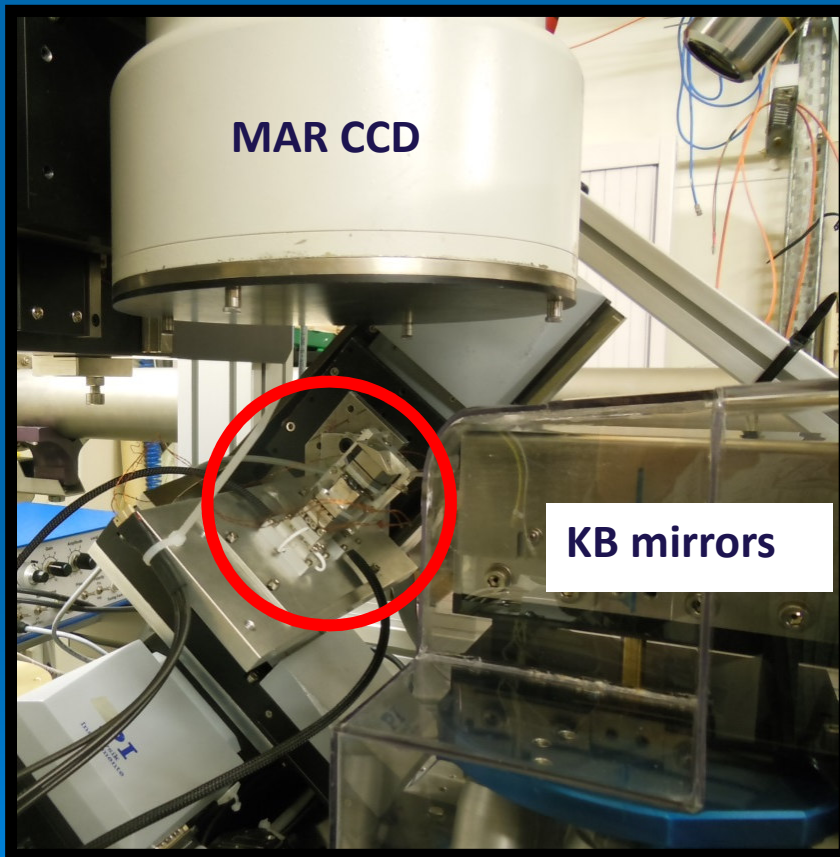


bending

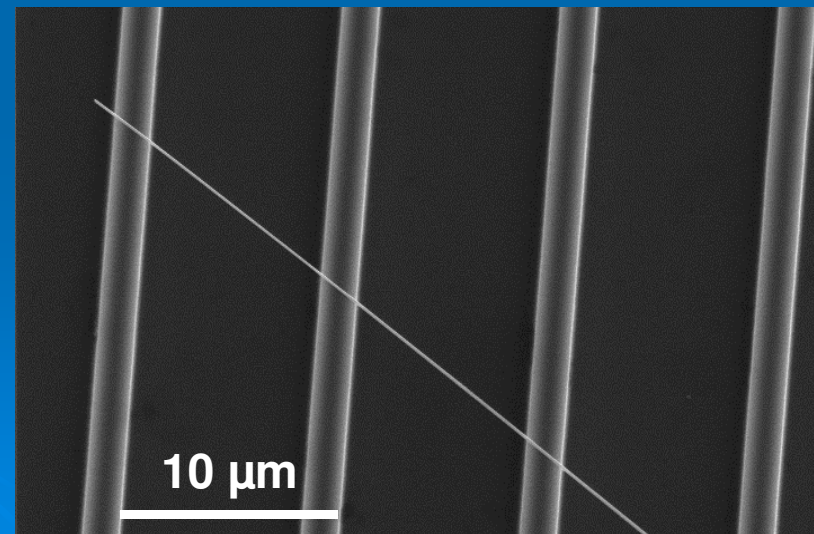
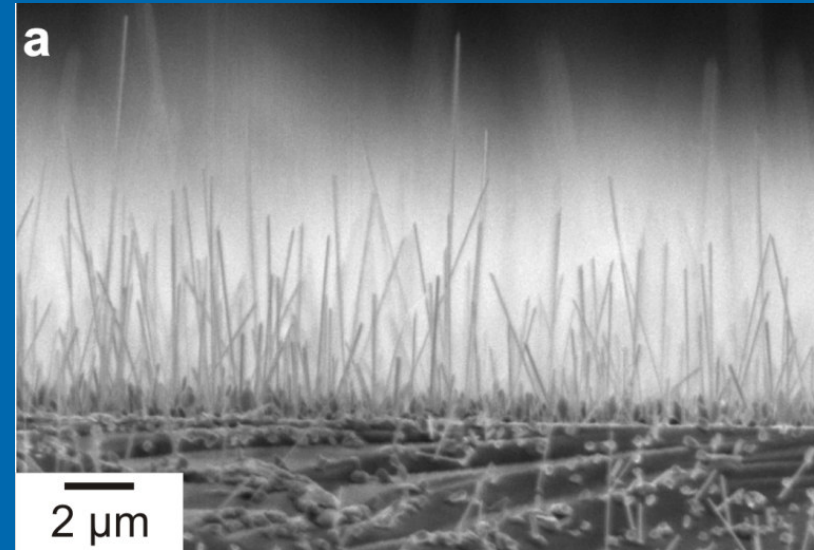
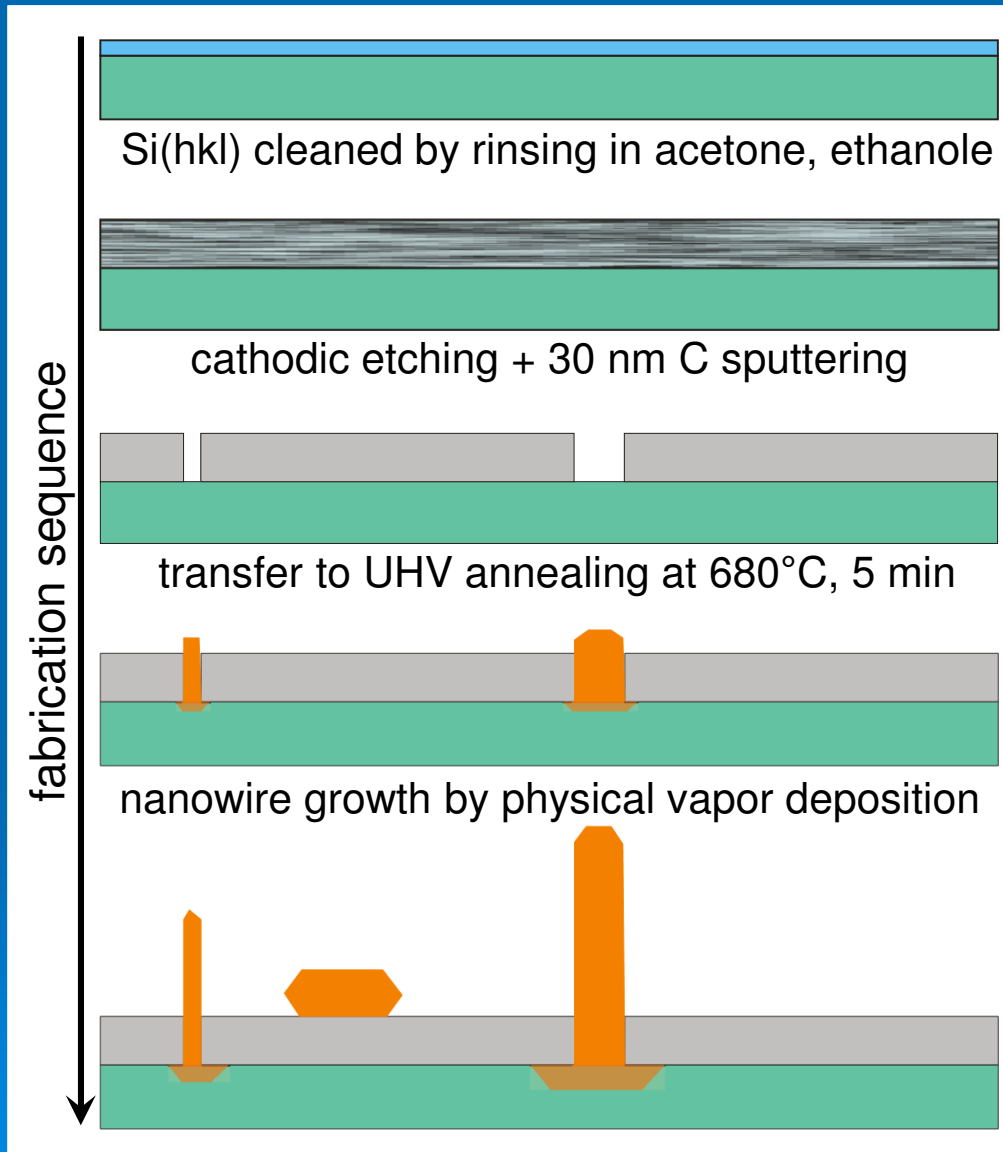


in situ μ Laue diffraction

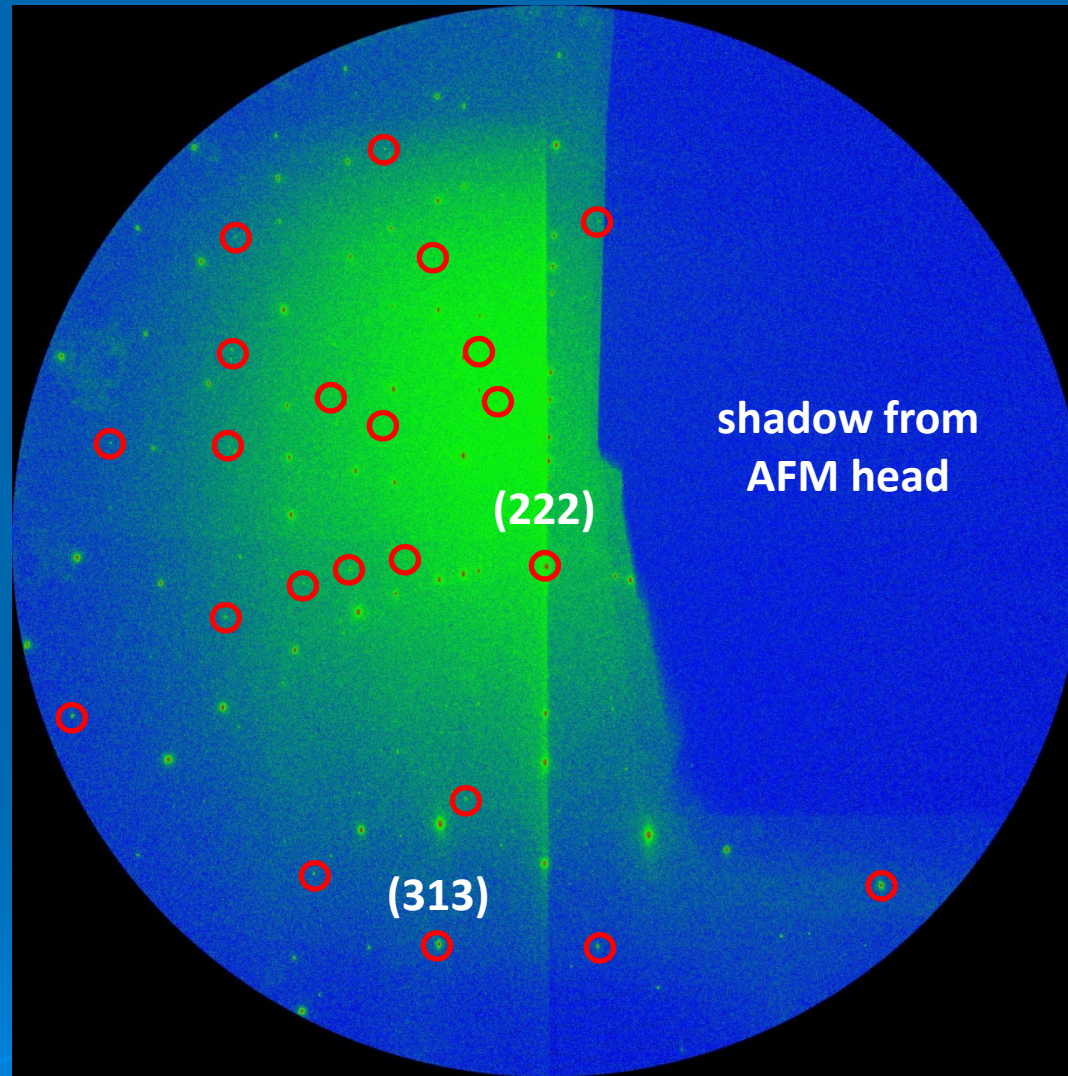
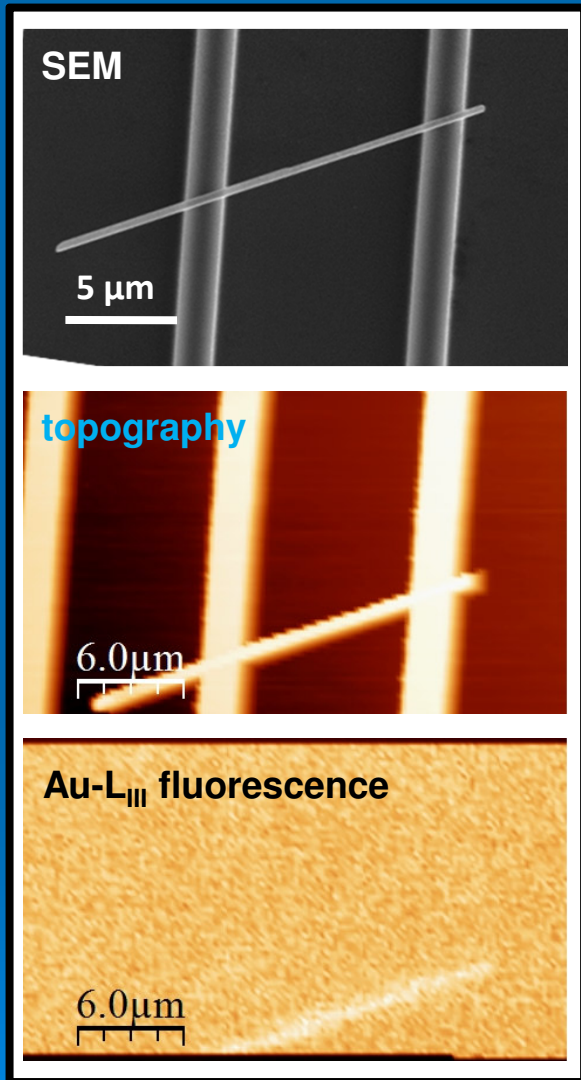
setup at BM32 @ ESRF



Au nanowires

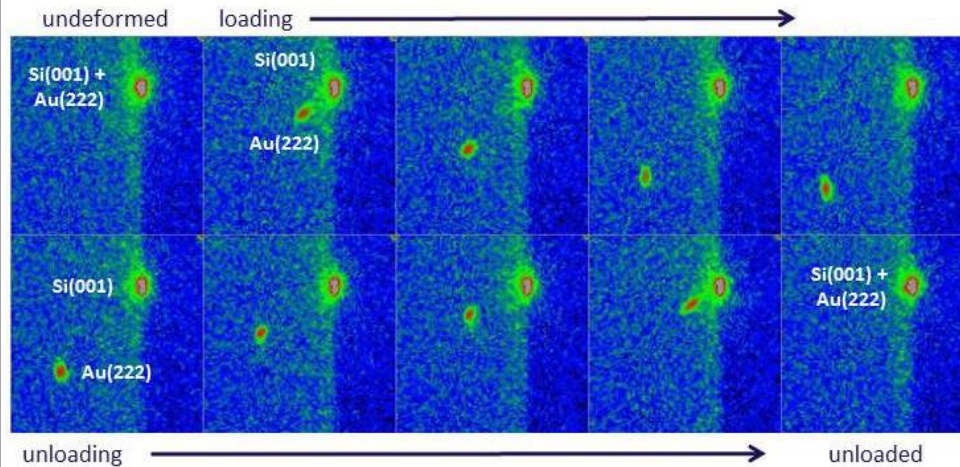


μ Laue diffraction

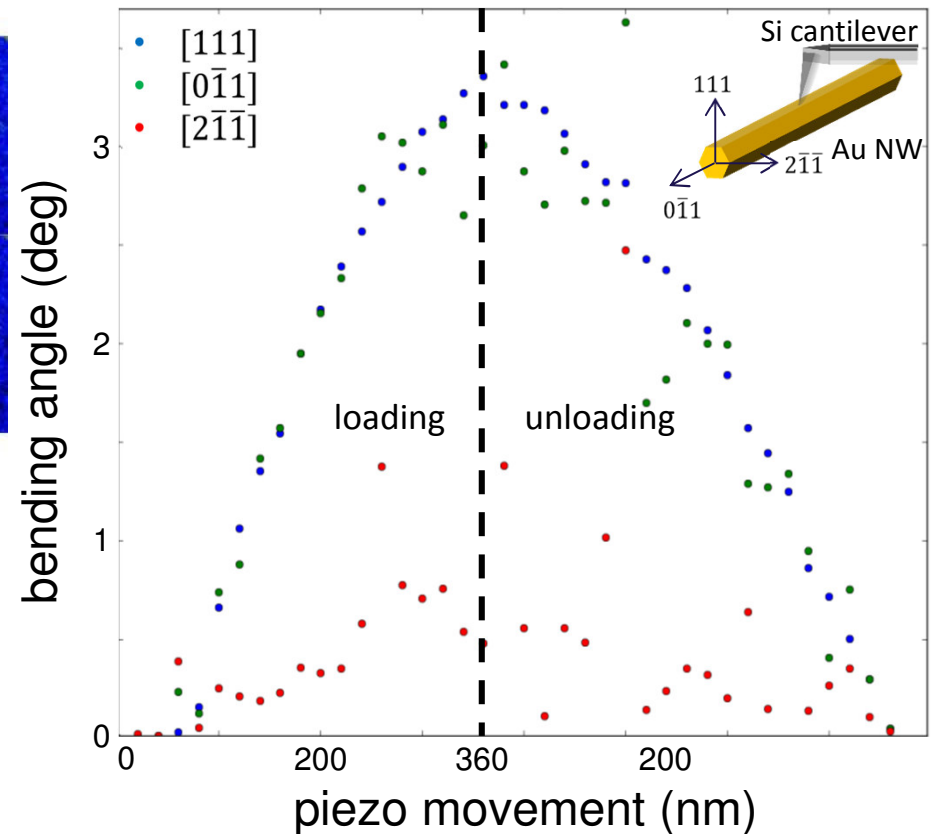


red circles indicate Laue spots from Au nanowire

nanowire bending

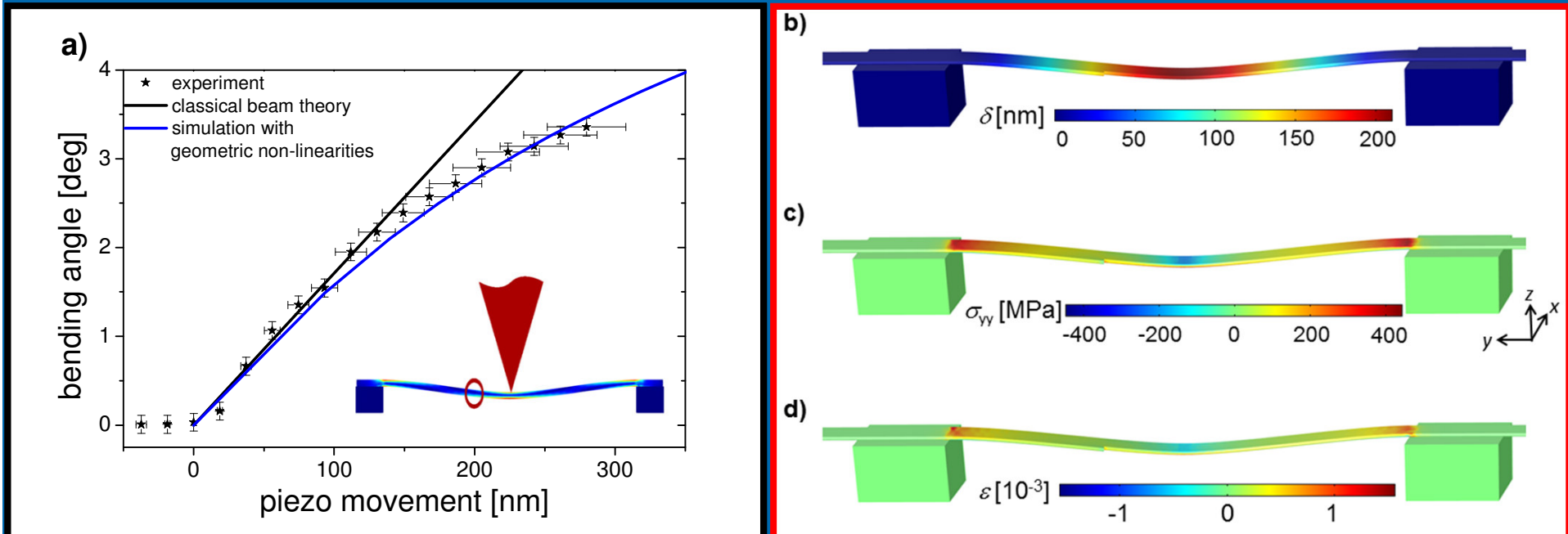


- **UB matrix computed from position and displacement of Laue spots**
- **calculation of crystal orientation – bending + rotation**



bending angle β increases up to 3.5° for $[111]$ and $[0\bar{1}1]$ direction, while for $[2\bar{1}\bar{1}]$ $\beta < 1^\circ$
 \Rightarrow force not perfectly vertical but finite lateral force exist due to cantilever deflection

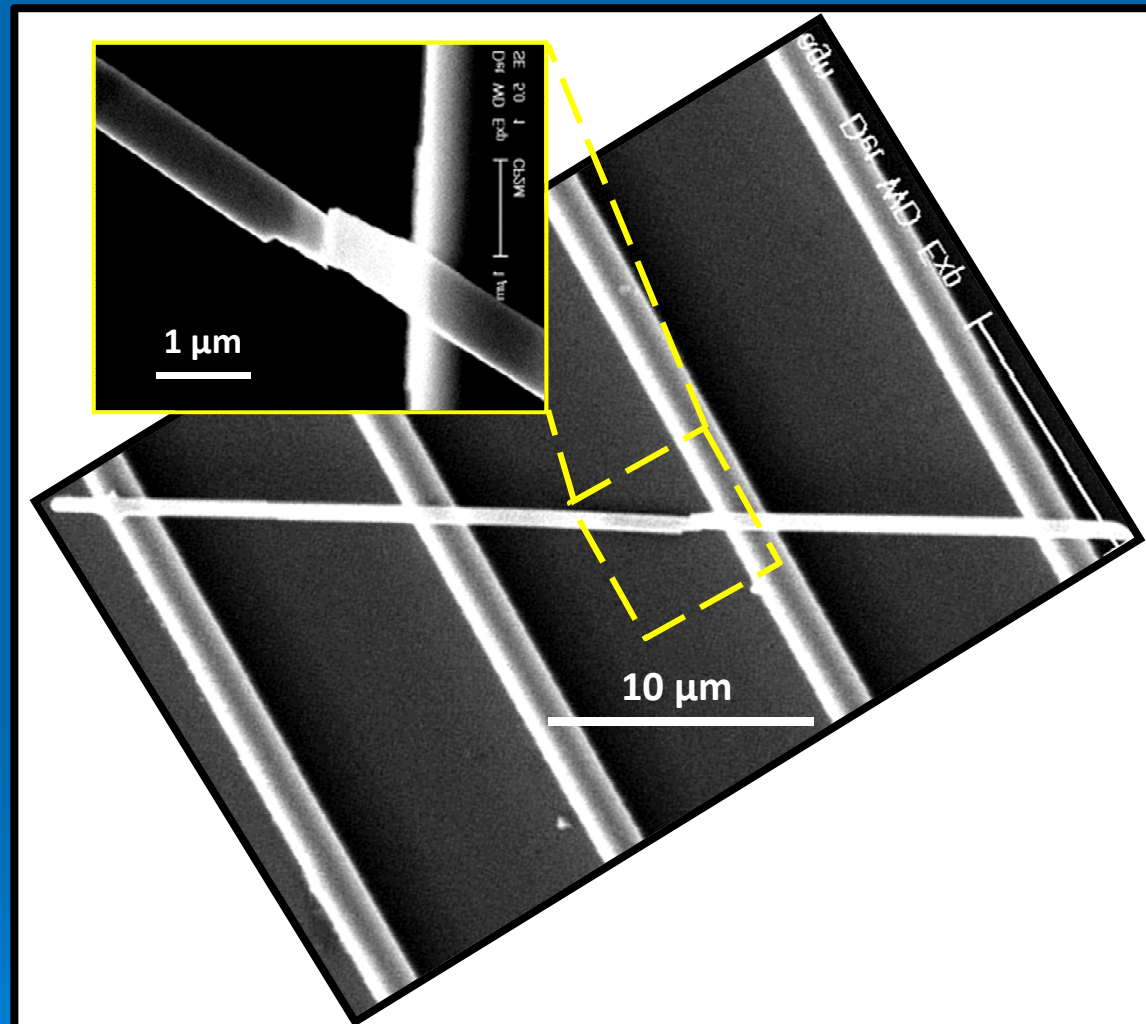
FEM simulation



experiment well described by FEM simulations

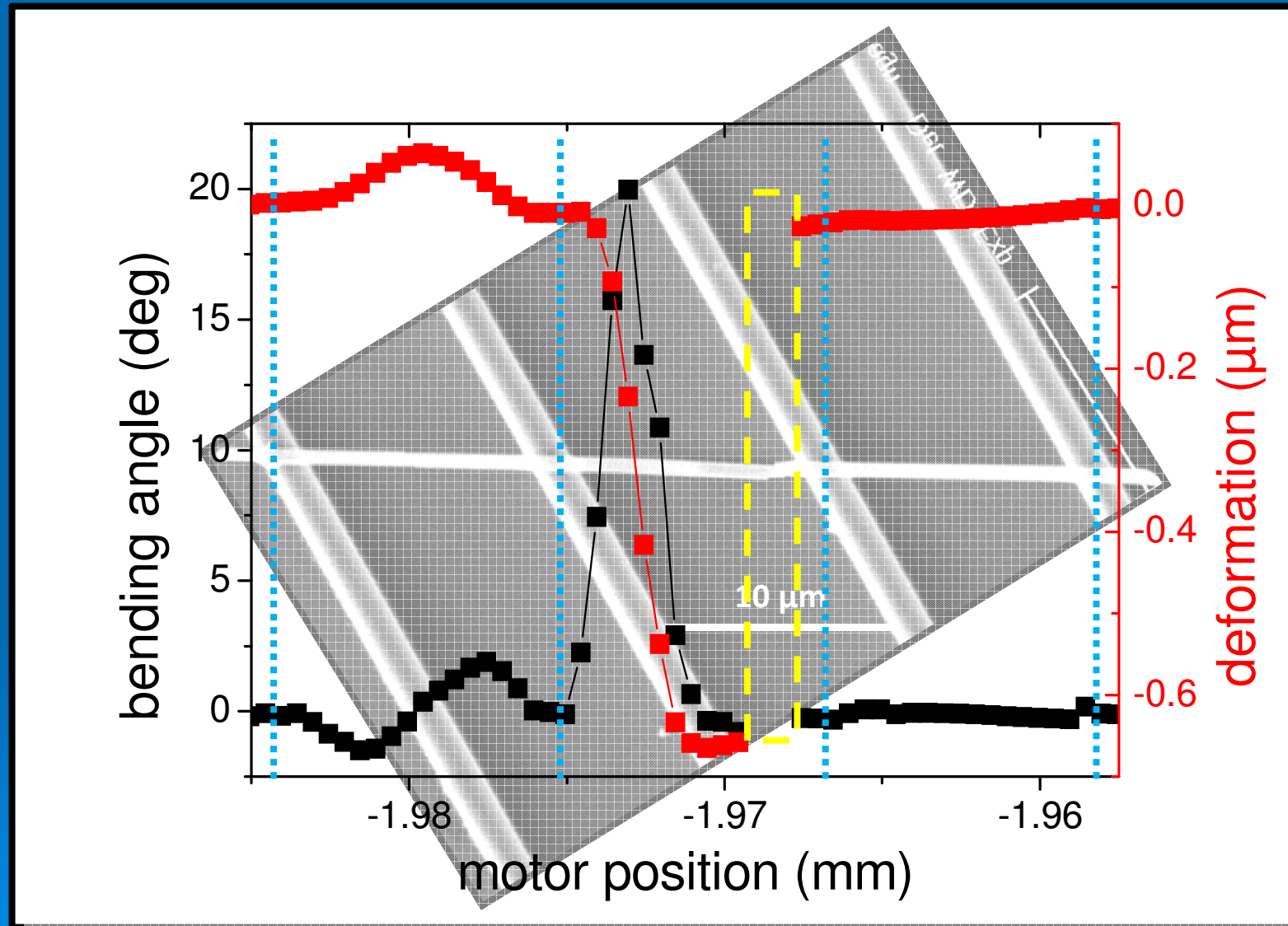
- bulk elastic constants
- geometric non-linearities due to strain inhomogeneity
- $\sigma_{\max} > 450 \text{ Mpa} \gg$ bulk yield strength
- max. theoretical shear stress for Au $\tau_{\max} = G/2\pi \sim 4.8 \text{ GPa}$

plasticity



- Au nanowires plastically deformed using AFM
- *Ex situ* scans with μ Laue diffraction along nanowire

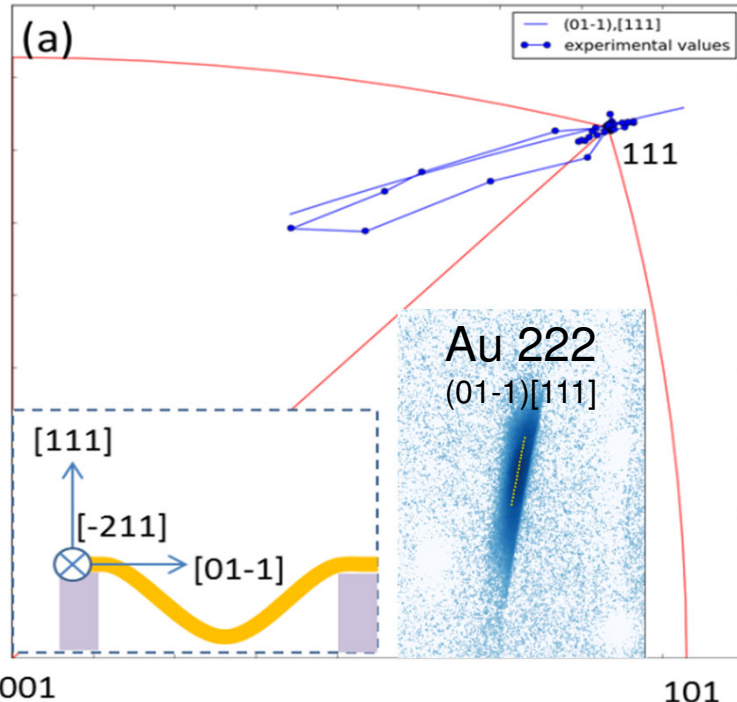
plasticity



identifying slip systems

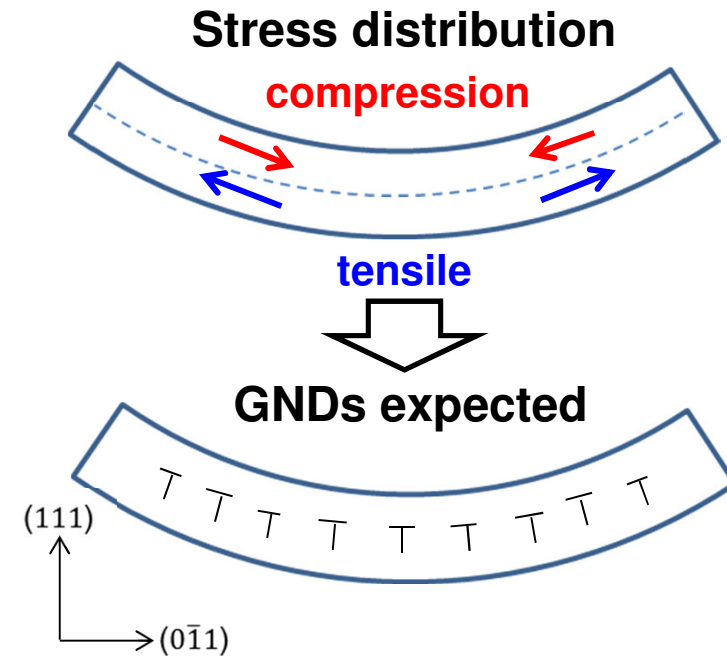
experiment

inverse pole figure



- mainly activated slip system: $(0-11), [111]$
- slight deviation observed
⇒ second slip system
- calculated geometry
⇒ clamped boundary conditions

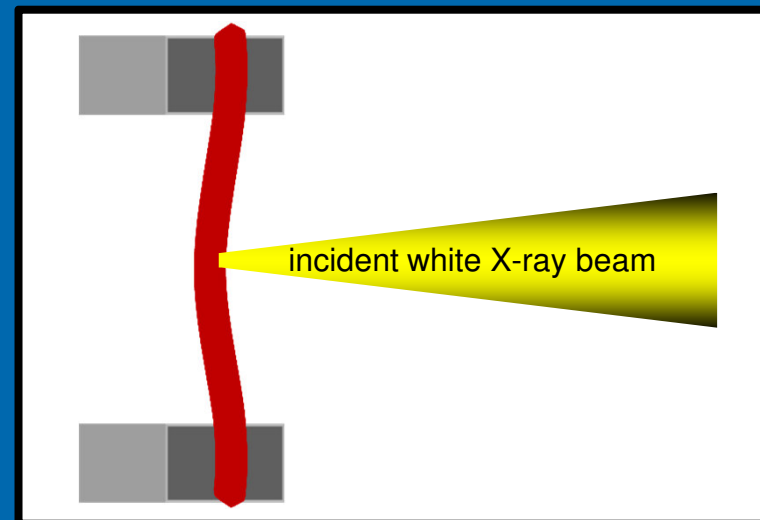
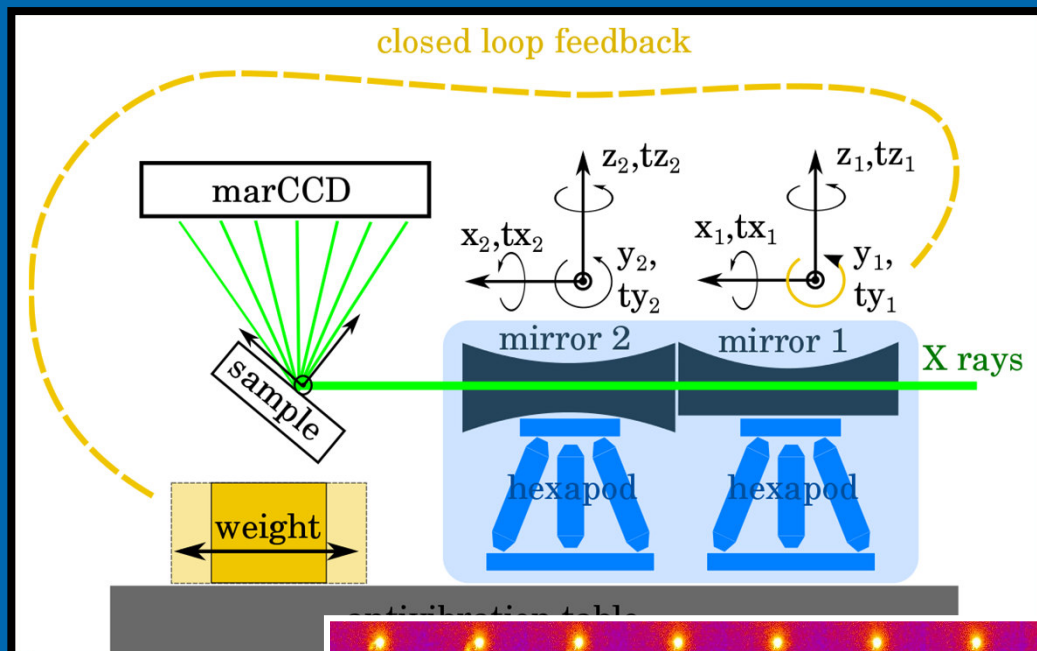
theory



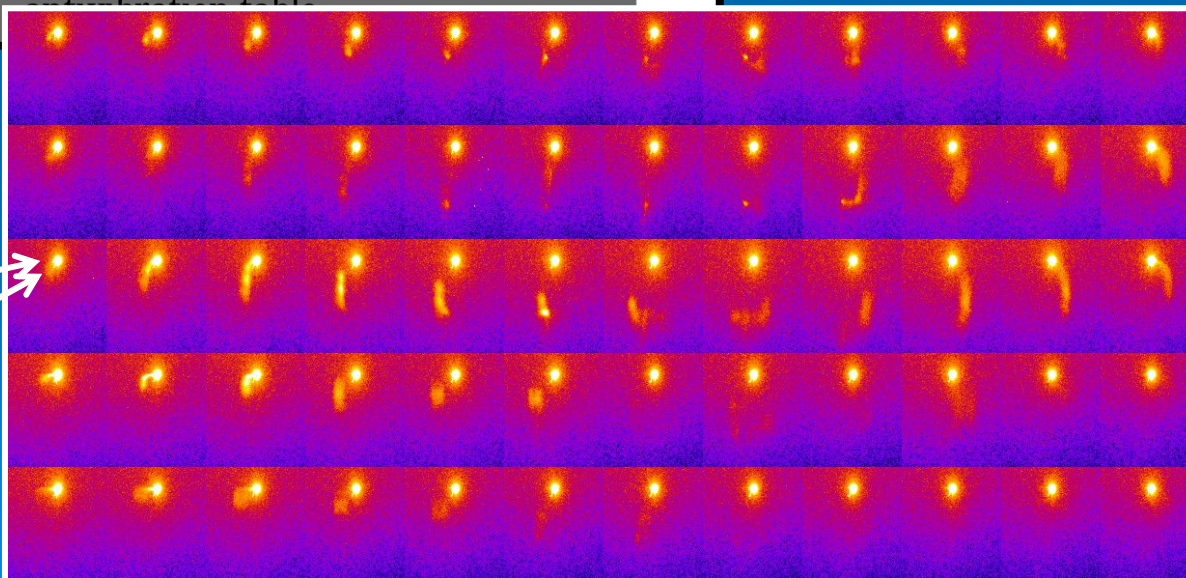
- expected slip system: $(0-11), [111]$
- dislocation stored for compatible deformation of crystal (GNDs)

N. Fleck et al., Acta Metall. Mater. 42 (1994) 475-487

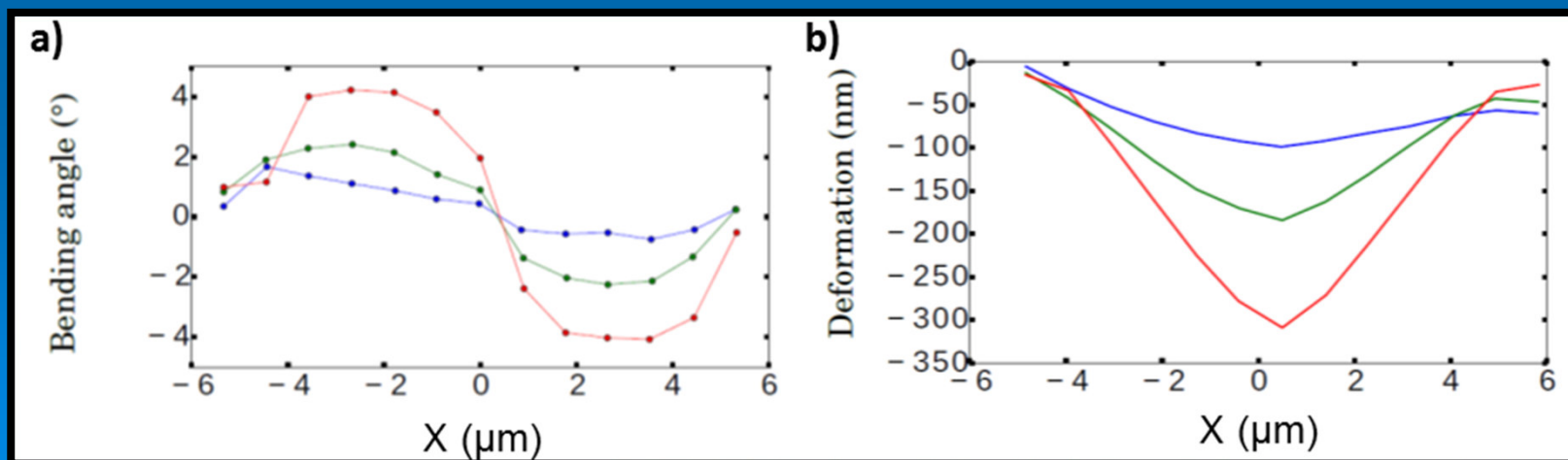
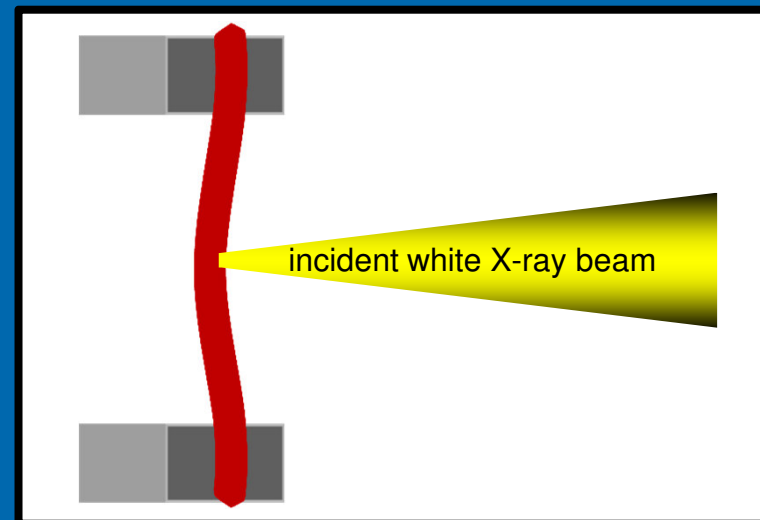
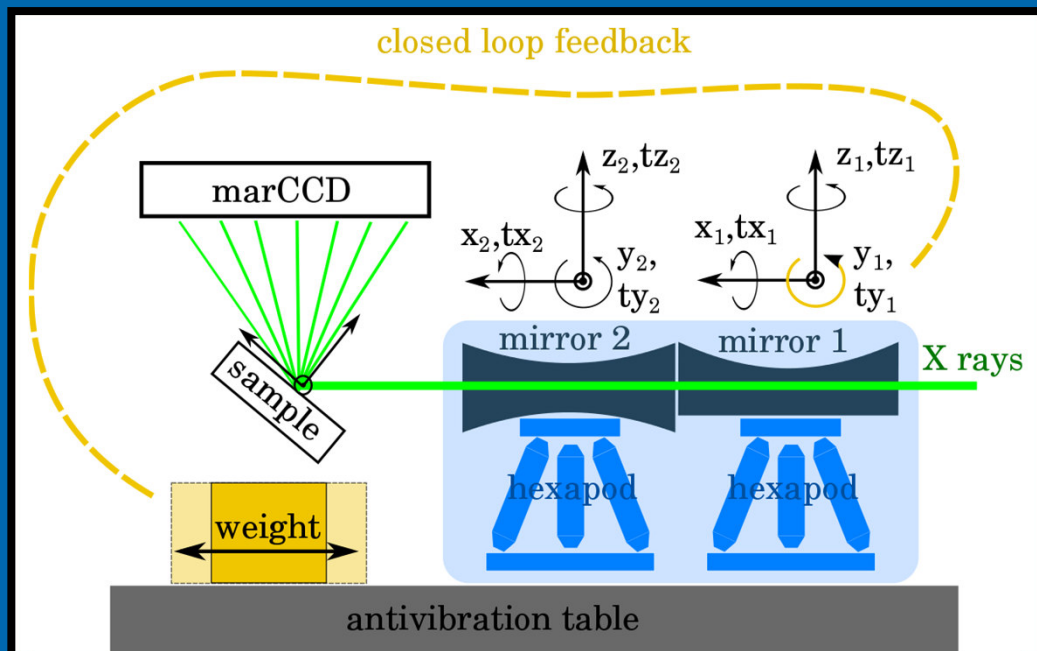
in situ KB scan



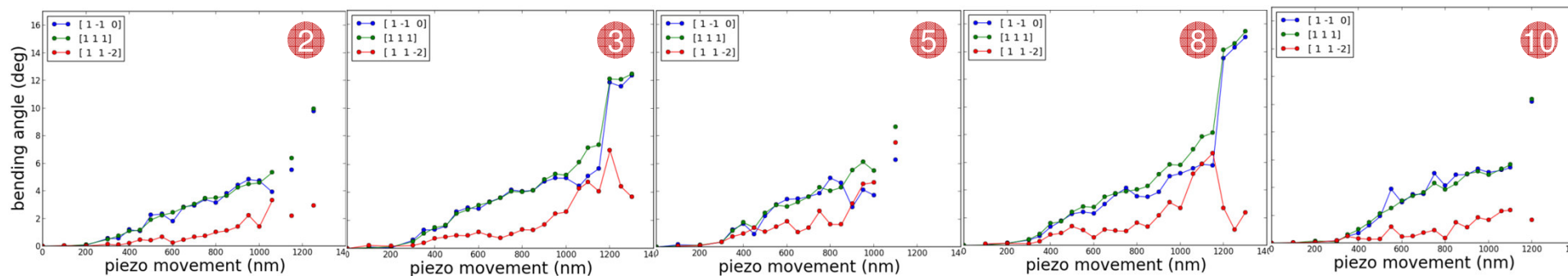
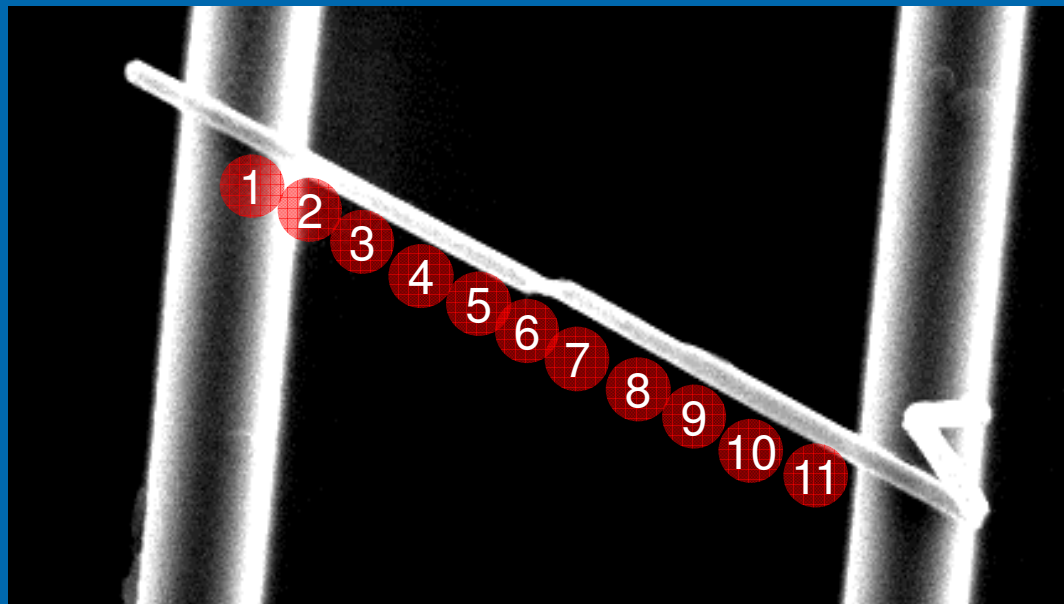
Si(004)
Au(222)



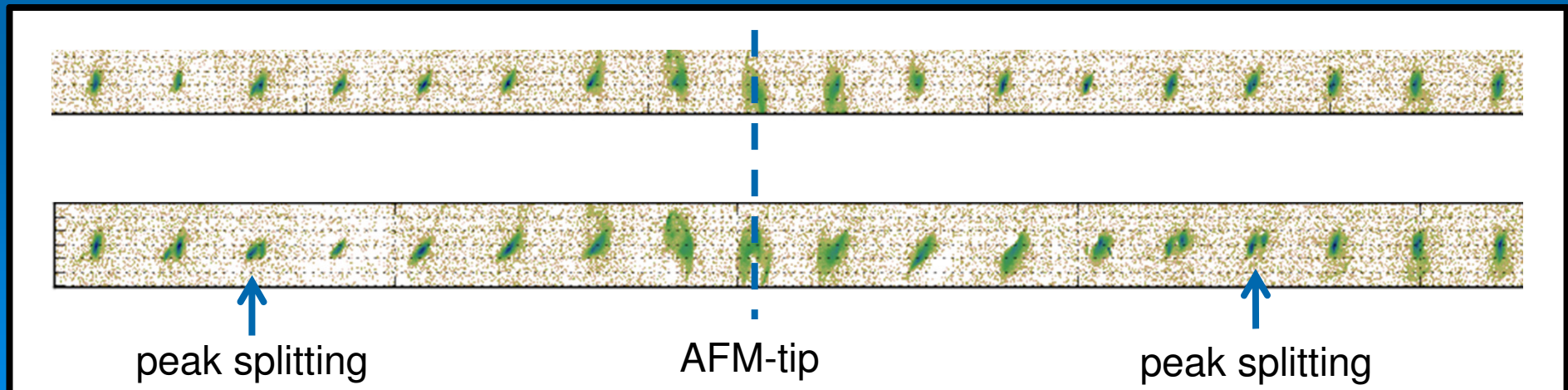
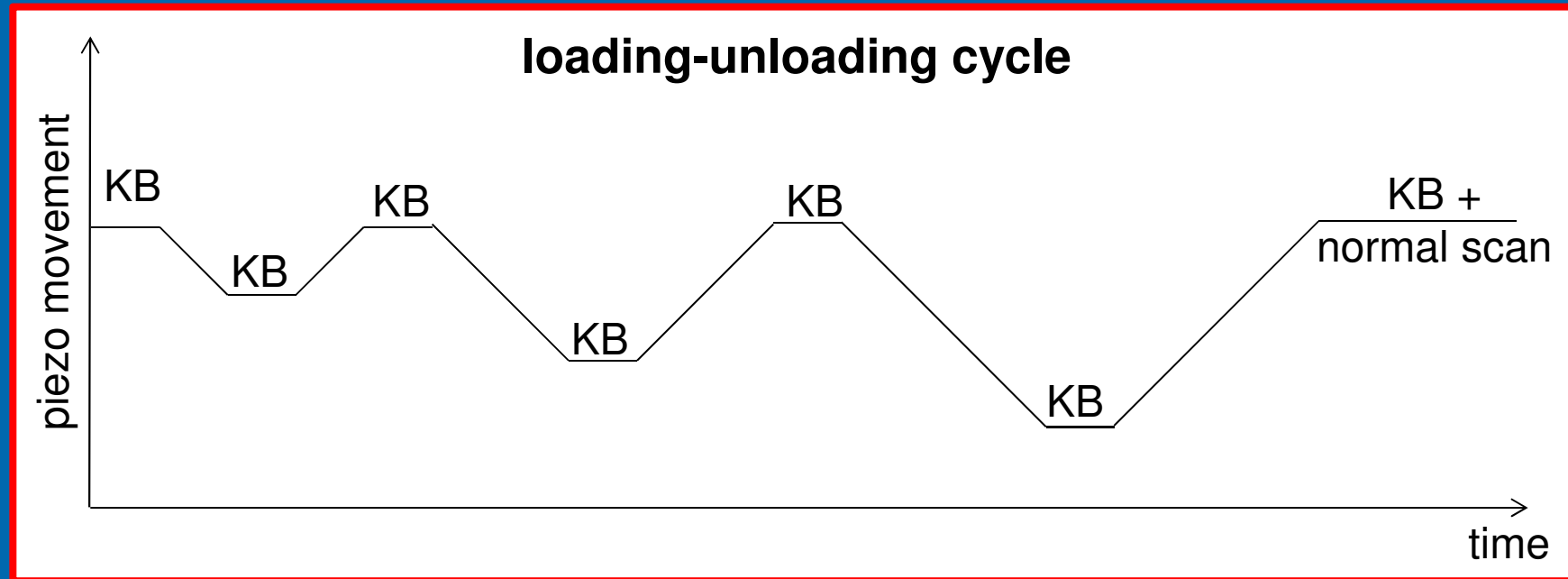
in situ KB scan



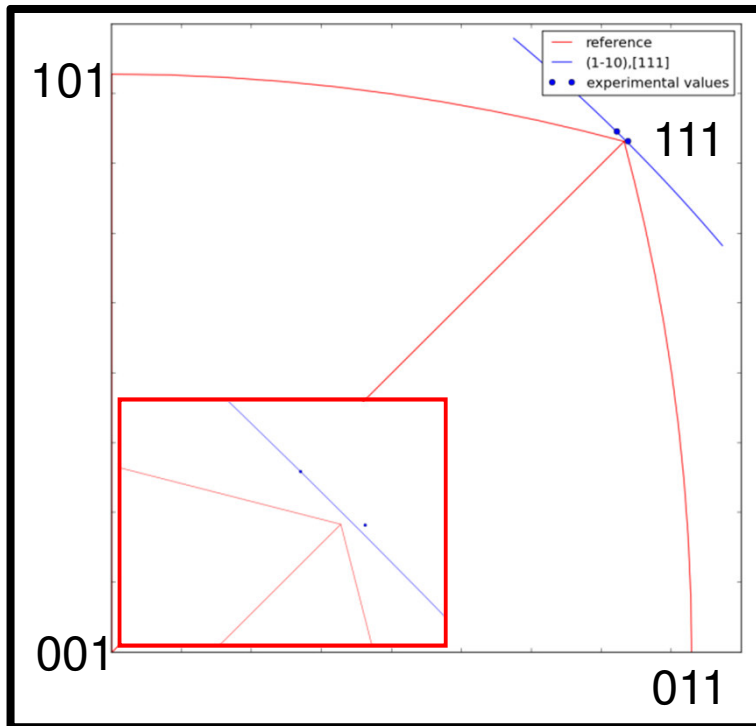
in situ KB scan



in situ plasticity



dislocations

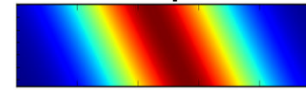


bending angles:
 $(11-2)=0.13^\circ$, $(1-10)=1.05^\circ$,
 $(111)=0.93^\circ$

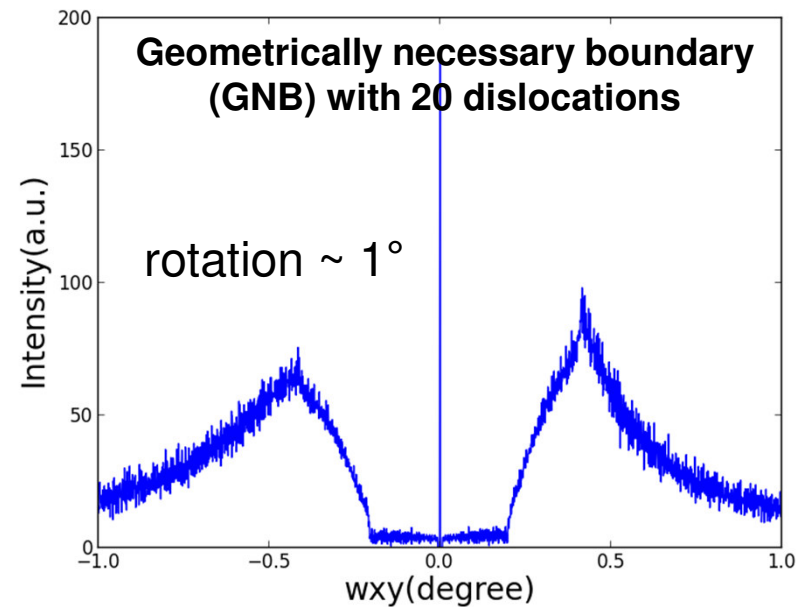
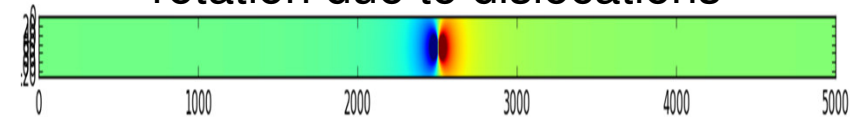
inverse pole figure indicates
single slip oriented

Calculations based on:
F. Hofmann et al., *Nature*
Comm. 4, 2774 (2013)

beam profile



rotation due to dislocations



facilitates « counting » number of dislocations

conclusions

Scanning force microscope for in situ nanofocused XRD

- ✓ Combination with μ Laue diffraction
- ✓ In-situ imaging
- ✓ Elastic bending of NWs
- ✓ Plastic deformation of NWs

In situ studies

- ✓ Elastic properties of NWs
- ✓ Defining activated slip system
- ✓ « counting » number of dislocations



General Meeting

on the Mechanics of Nano-objects

Marseille, November 5-6, 2015

Organizing Committee : Olivier Thomas, Cathy Paitel (IM2NP Marseille)



Registration deadline: October 11th, 2015

! Thanks for your attention !

